

<b>Notice of References Cited</b>	Application/Control No. 10/717,419	Applicant(s)/Patent Under Reexamination SEGAWA ET AL.	
	Examiner Allen C. Ho	Art Unit 2882	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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	B	US-6,590,953 B2	07-2003	Suzuki et al.	378/15
	C	US-6,241,668 B1	06-2001	Herzog, Norbert	600/407
	D	US-			
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	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
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**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Nicholas Tsoulfanidis. Measurement and Detection of Radiation, second edition (Washington, DC: Taylor & Francis, 1995), p. 567-570.
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\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.